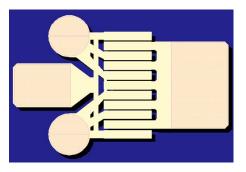
TGF2023-2-01

6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Product Overview

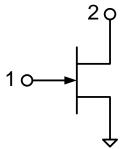
The Qorvo TGF2023-2-01 is a discrete 1.25 mm GaN on SiC HEMT which operates from DC-18 GHz. The TGF2023-2-01 is designed using Qorvo's proven QGaN25 production process. This process features advanced field plate techniques to optimize microwave power and efficiency at high drain bias operating conditions.

The TGF2023-2-01 typically provides 37.7 dBm of saturated output power with power gain of 20.7 dB at 3 GHz. The maximum power added efficiency is 71.6 % which makes the TGF2023-2-01 appropriate for high efficiency applications.



Lead-free and RoHS compliant

Functional Block Diagram



Pad Configuration

| Pad No. | Symbol |
|----------|-------------------------|
| 1 | V _G / RF IN |
| 2 | V _D / RF OUT |
| Backside | Source / Ground |

Key Features

- Frequency Range: DC 18 GHz
- Output Power (P_{3dB})¹: 38 dBm
- Maximum PAE¹: 71.6%
- Linear Gain¹: 18 dB
- Bias: V_D = 12 32 V, I_{DQ} = 25 125 mA
- Technology: TQGaN25 on SiC
- Chip Dimensions: 0.82 x 0.66 x 0.10 mm Note 1: @ 3 GHz

Applications

- Defense & Aerospace
- Broadband Wireless

Ordering Information

| Part Number | Description |
|--------------|-----------------|
| TGF2023-2-01 | 6 Watt GaN HEMT |

TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Absolute Maximum Ratings

| Parameter | Rating |
|------------------------------------------|--------------------|
| Drain to Gate Voltage (V _{DG}) | 100 V |
| Drain Voltage (V _D) | 40 V |
| Gate Voltage Range (V _G) | -7 to 2 V |
| Drain Current (I _D) | 1.438 A |
| Gate Current (I _G) | -1.25 to 3.5 mA |
| Power Dissipation, CW (P _D) | See graph on pg.4. |
| CW Input Power (P _{IN}) | +31 dBm |
| Storage Temperature | −65 to 150°C |

Exceeding any one or a combination of the Absolute Maximum Rating conditions may cause permanent damage to the device. Extended application of Absolute Maximum Rating conditions to the device may reduce device reliability.

Recommended Operating Conditions

| Parameter | Min | Тур | Max | Units |
|-------------------------------------------------|-------|------|------|-------|
| Drain Voltage Range (V _D) | +12 | +28 | +40 | V |
| Drain Quiescent Current (IDQ) | - | 62.5 | - | mA |
| Gate Voltage, V _G ¹ | -3.7 | -2.8 | -2.3 | V |
| Gate Leakage: $V_D = +10 V$, $V_G = -3.7 V$ | -1.25 | _ | - | mA |

Electrical specifications are measured at specified test conditions. Specifications are not guaranteed over all recommended operating conditions. Note:

1. To be adjusted to desired I_{DQ}

RF Characterization – Model Optimum Power Tune

Test conditions unless otherwise noted: $T = 25^{\circ}C$, Pulse (10% Duty Cycle, 100 μ s Width).

| Parameter | | Typical Value | | | | | | Units | |
|-------------------------------------------------------|----------|---------------|-----------|-----------|-----------|-----------|-----------|-----------|-------|
| Frequency (F) | 3 | 5 | | 6 | 8 | 3 | 1 | 0 | GHz |
| Drain Voltage (V _D) | 28 | 28 | 28 | 28 | 28 | 28 | 28 | 28 | V |
| Bias Current (I _{DQ}) | 25 | 62.5 | 25 | 62.5 | 25 | 62.5 | 25 | 62.5 | mA |
| Output P3dB (P _{3dB}) | 38 | 37.8 | 38.1 | 38.0 | 38.1 | 38.0 | 38.1 | 38.0 | dBm |
| Drain Eff. @ P _{3dB} (DE _{3dB}) | 60.2 | 59.1 | 57.7 | 57.3 | 55.4 | 55.6 | 53 | 53.3 | % |
| Gain @ P3dB (G _{3dB}) | 20 | 20.8 | 14.6 | 15.4 | 12.2 | 13 | 10.4 | 11.2 | dB |
| Parallel Resistance (1) (Rp) | 65.2 | 65.1 | 63.1 | 62.7 | 59.3 | 59.7 | 56.1 | 55.8 | Ω·mm |
| Parallel Capacitance ⁽¹⁾ (C _p) | 0.318 | 0.312 | 0.324 | 0.321 | 0.341 | 0.343 | 0.328 | 0.330 | pF/mm |
| Load Reflection Coefficient $^{(2)}$ ($\Gamma_{L})$ | 0.19∠94° | 0.19∠95° | 0.36∠110° | 0.35∠110° | 0.46∠120° | 0.47∠120° | 0.52∠126° | 0.52∠127° | |

Notes:

1. Large signal equivalent output network (normalized).

2. Characteristic Impedance (Zo) = 50 Ω .

RF Characterization – Model Optimum Efficiency Tune

Test conditions unless otherwise noted: $T = 25^{\circ}C$, Pulse (10% Duty Cycle, 100 μ s Width).

| Parameter | | Typical Value | | | | | | Units | |
|------------------------------------------------------|----------|---------------|----------|----------|-----------|-----------|-----------|-----------|-------|
| Frequency (F) | 3 | 5 | | 6 | 8 | 3 | 1 | 0 | GHz |
| Drain Voltage (V _D) | 28 | 28 | 28 | 28 | 28 | 28 | 28 | 28 | V |
| Bias Current (IDQ) | 25 | 62.5 | 25 | 62.5 | 25 | 62.5 | 25 | 62.5 | mA |
| Output P3dB (P _{3dB}) | 36.8 | 36.7 | 37.0 | 37.0 | 37 | 37.1 | 37.1 | 37.1 | dBm |
| Drain Eff. @ P _{3dB} (DE _{3dB}) | 65.6 | 64.3 | 63.3 | 62.5 | 60.5 | 60.1 | 57.3 | 57.4 | % |
| Gain @ P3dB (G _{3dB}) | 21.6 | 22.4 | 15.9 | 16.6 | 13.3 | 14.1 | 11.4 | 12.2 | dB |
| Parallel Resistance ⁽¹⁾ (R _p) | 110 | 112 | 104 | 100 | 99.8 | 94.4 | 88.9 | 85.9 | Ω·mm |
| Parallel Capacitance (1) (Cp) | 0.398 | 0.384 | 0.394 | 0.390 | 0.394 | 0.390 | 0.384 | 0.386 | pF/mm |
| Load Reflection Coefficient $^{(2)}$ ($\Gamma_{L})$ | 0.39∠64° | 0.39∠62° | 0.55∠97° | 0.53∠97° | 0.63∠110° | 0.62∠111° | 0.68∠120° | 0.67∠121° | |

Notes:

1. Large signal equivalent output network (normalized).

2. Characteristic Impedance (Zo) = 50Ω .

TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Thermal and Reliability Information - CW⁽¹⁾

| Parameter | Test Conditions | Value | Units |
|---------------------------------------------------------------------------------------|-----------------------------------------------|-------|-------|
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | P _{DISS} = 1.25 W, Tbaseplate = 85°C | 12.7 | °C/W |
| Channel Temperature, TCH | | 101 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | P _{DISS} = 2.5 W, Tbaseplate = 85°C | 14.1 | °C/W |
| Channel Temperature, T _{CH} | | 120 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | P _{DISS} = 3.75 W, Tbaseplate = 85°C | 14.7 | °C/W |
| Channel Temperature, T _{CH} | | 140 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | P _{DISS} = 5.00 W, Tbaseplate = 85°C | 15.2 | °C/W |
| Channel Temperature, T _{CH} | | 161 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | P _{DISS} = 6.25 W, Tbaseplate = 85°C | 15.9 | °C/W |
| Channel Temperature, Тсн | | 184 | °C |

Notes:

1. Refer to the following document: GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates

Thermal and Reliability Information - Pulsed ⁽¹⁾

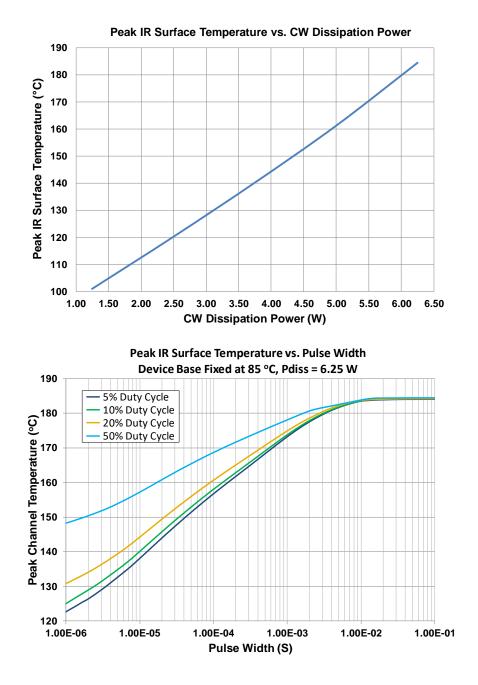
| Parameter | Test Conditions | Value | Units |
|------------------------------------------------------------------------------------|----------------------------------------------------------------------------------|-------|-------|
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | $P_{DISS} = 6.25 W$, Tbaseplate = $85^{\circ}C$ Pulse Width = 100 uS | 11.5 | °C/W |
| Channel Temperature, T _{CH} | Duty Cycle = 5% | 157 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | P _{DISS} = 6.25 W, Tbaseplate = 85°C Pulse Width = 100 uS | 11.7 | °C/W |
| Channel Temperature, T _{CH} | Duty Cycle = 10% | 158 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | $P_{DISS} = 6.25 \text{ W}$, Tbaseplate = $85^{\circ}C$ Pulse Width = 100 uS | 12.1 | °C/W |
| Channel Temperature, T _{CH} | Duty Cycle = 20% | 161 | °C |
| Thermal Resistance, Peak IR Surface Temperature at Average Power (θ_{JC}) | $P_{DISS} = 6.25 \text{ W}$, Tbaseplate = $85^{\circ}C$ Pulse Width = 100 uS | 13.8 | °C/W |
| Channel Temperature, Тсн | Duty Cycle = 50% | 171 | °C |

Notes:

1. Refer to the following document: GaN Device Channel Temperature, Thermal Resistance, and Reliability Estimates

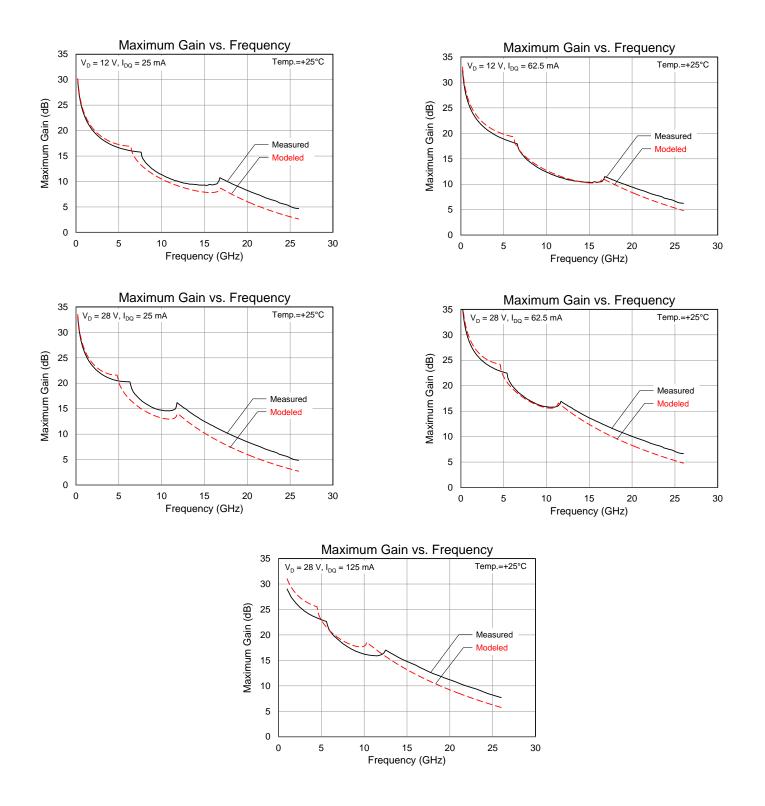
TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Maximum Channel Temperature



TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

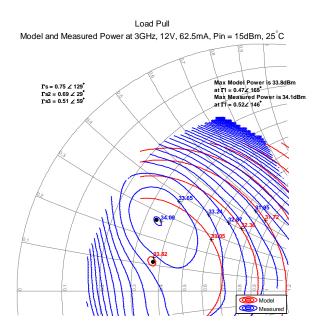
Model Maximum Gain Performance

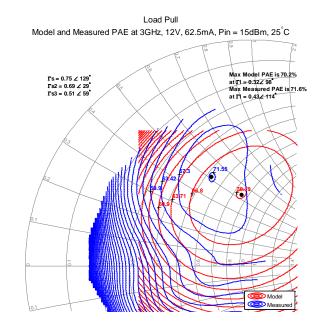


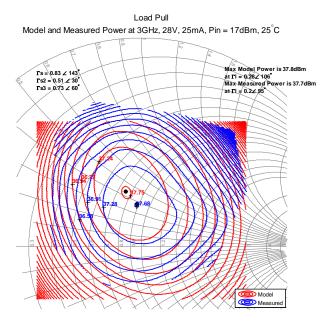
TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Model Load Pull Contours

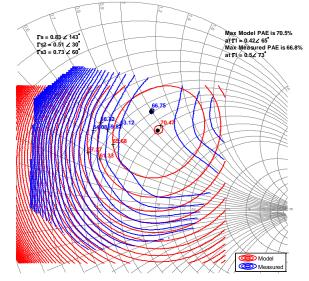
Load pull signal: Pulse (10% Duty Cycle, 100 µs Width). Bond wires included. Measured data provided by Modelithics.







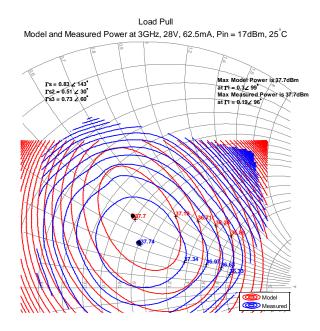
Load Pull Model and Measured PAE at 3GHz, 28V, 25mA, Pin = 17dBm, $25^{\circ}C$

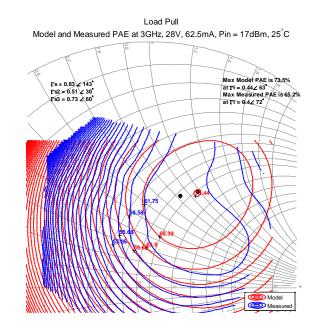


TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Model Load Pull Contours

Load pull signal: Pulse (10% Duty Cycle, 100 µs Width). Bond wires included. Measured data provided by Modelithics.

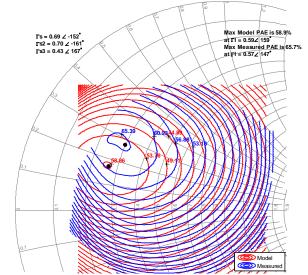




Model and Measured Power at 10GHz, 28V, 62.5mA, Pin = 27dBm, 25 °C

Load Pull

Load Pull Model and Measured PAE at 10GHz, 28V, 62.5mA, Pin = 27dBm, 25 $^\circ \rm C$



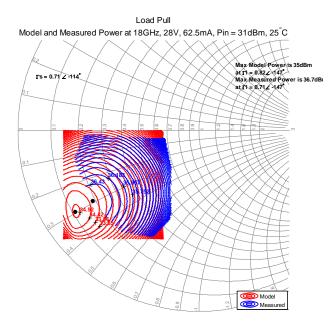
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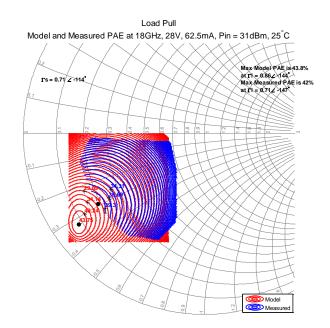
Model
Measure

TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Model Load Pull Contours

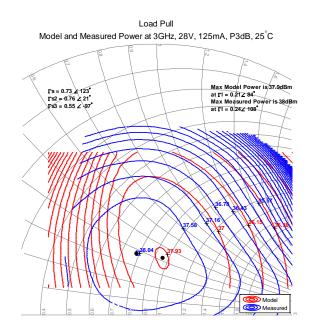
Load pull signal: Pulse (10% Duty Cycle, 100 µs Width). Bond wires included. Measured data provided by Modelithics.

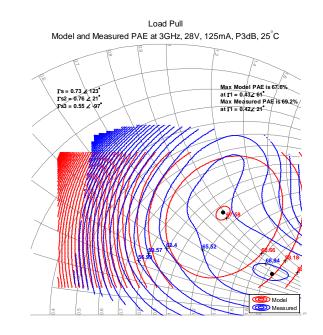




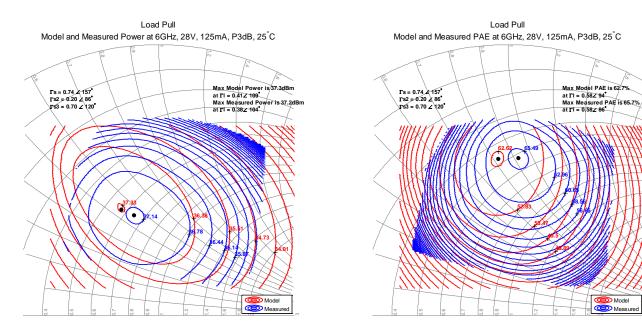


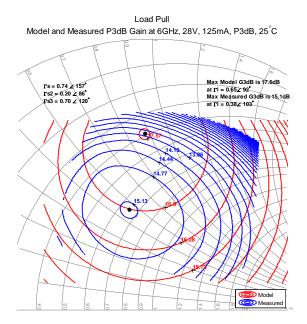
Model Load Pull Contours





Model Load Pull Contours

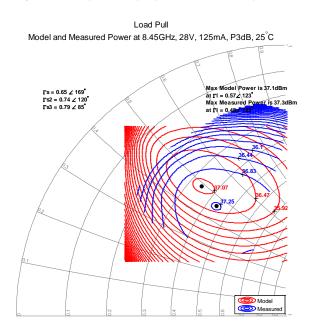


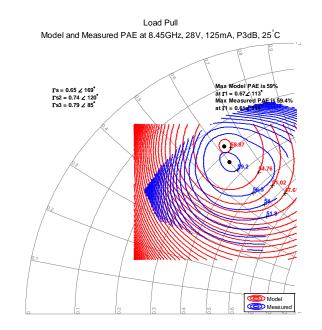




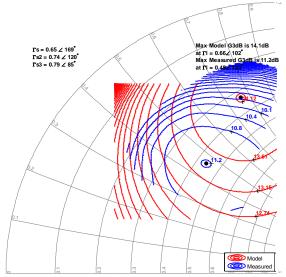
TGF2023-2-01 6 W, 32 V, DC to 18 GHz, Discrete Power GaN on SiC HEMT

Model Load Pull Contours



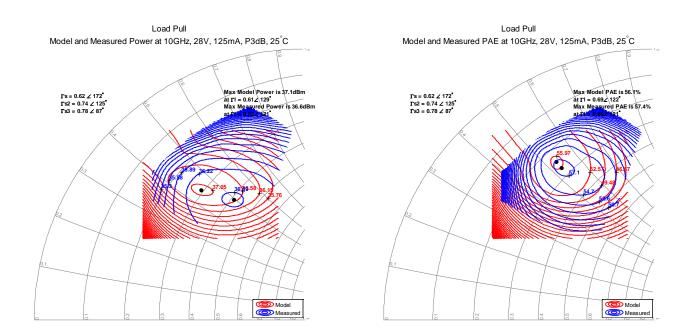


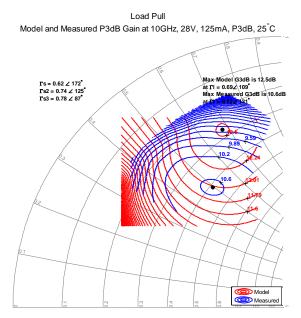
Load Pull Model and Measured P3dB Gain at 8.45GHz, 28V, 125mA, P3dB, 25 $^\circ\text{C}$



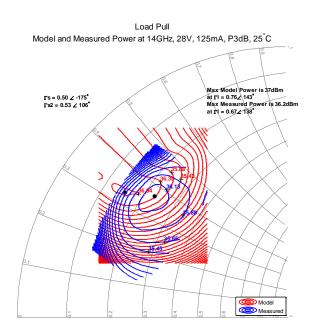


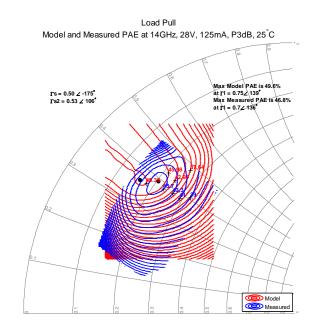
Model Load Pull Contours

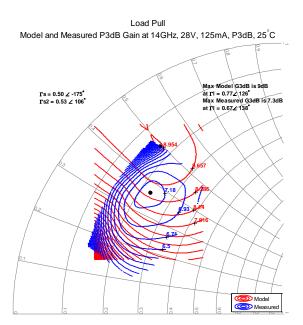




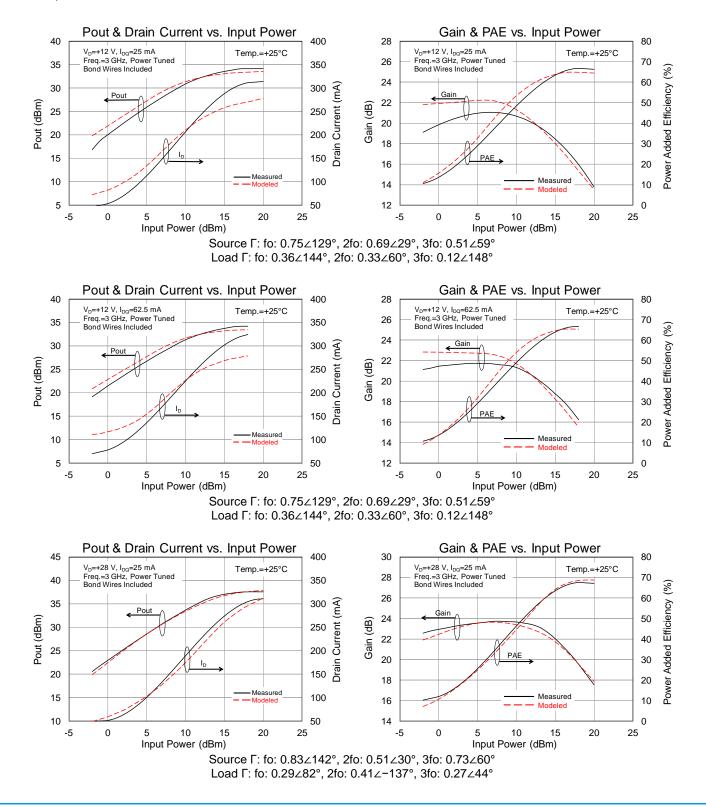
Model Load Pull Contours



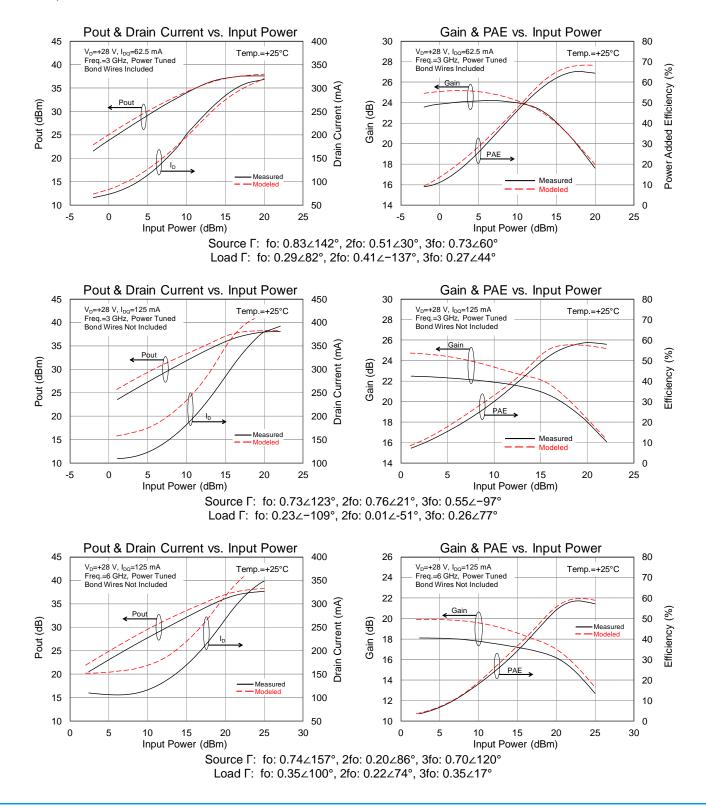




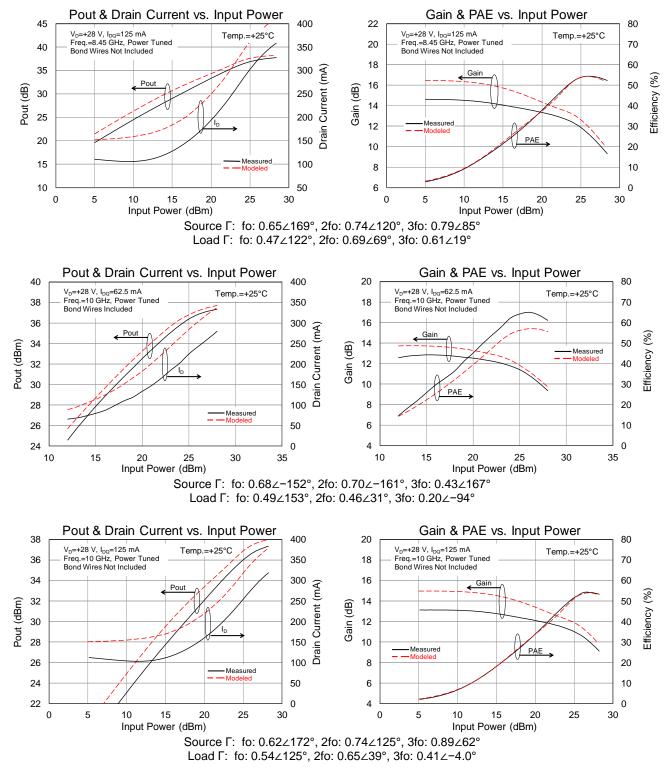
Measured Power Tuned Data



Measured Power Tuned Data

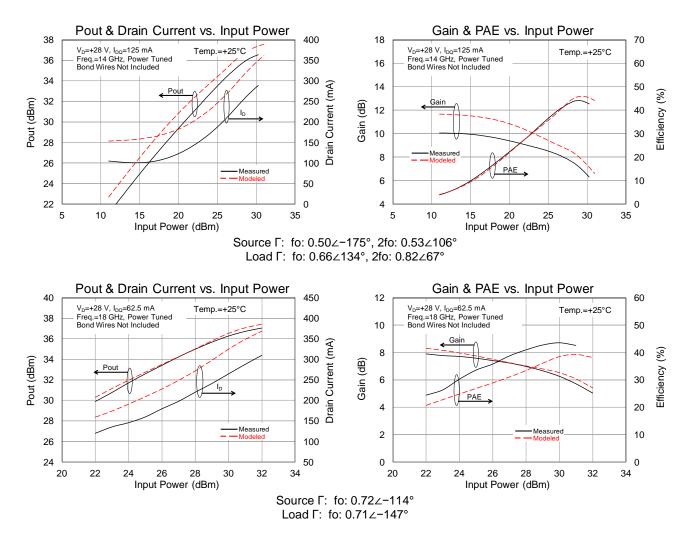


Measured Power Tuned Data

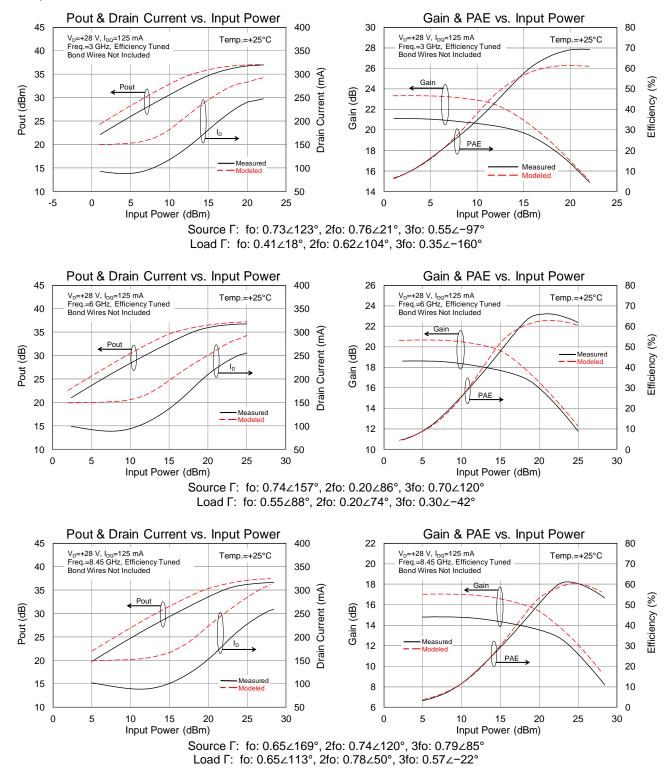




Measured Power Tuned Data

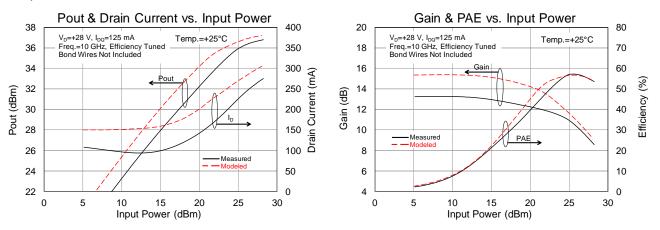


Measured Efficiency Tuned Data

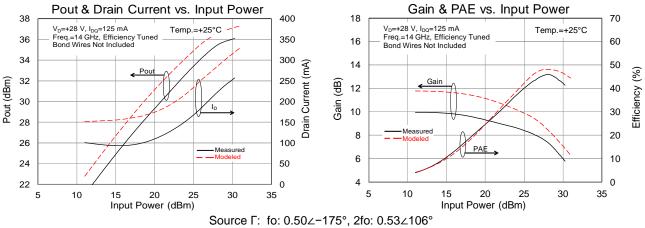


Measured Efficiency Tuned Data

Modelithics provided measured data at 25mA and 62.5mA bias currents.



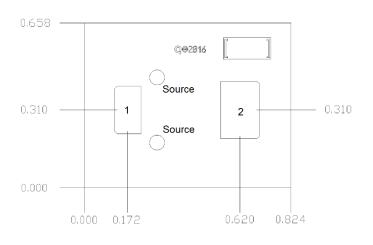
Source Γ: fo: 0.62∠172°, 2fo: 0.74∠125°, 3fo: 0.89∠62° Load Γ: fo: 0.68∠120°, 2fo: 0.69∠34°, 3fo: 0.41∠−17°



Load Γ: fo: 0.73∠134°, 2fo: 0.84∠71°



Mechanical Drawing



Bond Pads

| Pad No. | Description | Dimensions |
|--------------|-----------------|---------------|
| 1 | Gate | 0.154 x 0.115 |
| 2 | Drain | 0.154 x 0.230 |
| Die Backside | Source / Ground | 0.662 x 0.824 |

- 1. Units: millimeters
- 2. Thickness: 0.100 mm
- 3. Die xy size tolerance: ± 0.050 mm



Model

A model is available for download from Modelithics (at <u>http://www.modelithics.com/mvp/Triquint&tab=3</u>) by approved Qorvo customers. The model is compatible with the industry's most popular design software including Agilent ADS and National Instruments/AWR applications. Once on the Modelithics web page, the user will need to register for a free license before being granted the download.

Assembly Notes

Component placement and adhesive attachment assembly notes:

- Vacuum pencils and/or vacuum collets are the preferred method of pick up.
- Air bridges must be avoided during placement.
- The force impact is critical during auto placement.
- Organic attachment (i.e. epoxy) not recommended.

Reflow process assembly notes:

- Use AuSn (80/20) solder and limit exposure to temperatures above 300°C to 3-4 minutes, maximum.
- An alloy station or conveyor furnace with reducing atmosphere should be used.
- Do not use any kind of flux.
- Coefficient of thermal expansion matching is critical for long-term reliability.
- Devices must be stored in a dry nitrogen atmosphere.

Interconnect process assembly notes:

- Ball bonding is the preferred interconnect technique, except where noted on the assembly diagram.
- Force, time, and ultrasonics are critical bonding parameters.
- Aluminum wire should not be used.
- Devices with small pad sizes should be bonded with 0.0007-inch wire.



Disclaimer

GaN/SiC devices are susceptible to damage from Electrostatic Discharge. Proper precautions should be observed during handling, assembly and test.

Bias Procedure

| Bias-Up Procedure | Bias-Down Procedure |
|------------------------------------------------------------------------|----------------------------------------------------------------|
| 1. Set V_G to -5 V. | 1. Turn off RF signal. |
| 2. Apply +28 V to V_D . | 2. Turn off V _D . |
| 3. Slowly adjust V _G until I _D is set to 125 mA. | 3. Wait two (2) seconds to allow drain capacitor to discharge. |
| 4. Apply RF. | 4. Turn off V _G . |
| | • |



Handling Precautions

| Parameter | Rating | Standard | |
|--------------------------------|--------|---------------------------------|----------------------|
| ESD-Human Body Model (HBM) | TBD | ANSI/ESDA/JEDEC Standard JS-001 | |
| ESD-Charged Device Model (CDM) | N/A | ANSI/ESDA/JEDEC Standard JS-002 | |
| MSL-Moisture Sensitivity Level | N/A | IPC/JEDEC Standard J-STD-020 | Caution! |
| | | | ESD-Sensitive Device |

Solderability

Compatible with gold/tin (320°C maximum reflow temperature) soldering processes.

RoHS Compliance

This part is compliant with 2011/65/EU RoHS directive (Restrictions on the Use of Certain Hazardous Substances in Electrical and Electronic Equipment) as amended by Directive 2015/863/EU.

This product also has the following attributes:

- Lead Free
- Halogen Free (Chlorine, Bromine)
- Antimony Free
- TBBP-A (C₁₅H₁₂Br₄0₂) Free
- PFOS Free
- SVHC Free

Contact Information

For the latest specifications, additional product information, worldwide sales and distribution locations:

Web: <u>www.qorvo.com</u>

Email: customer.support@gorvo.com



Tel: 1-844-890-8163

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